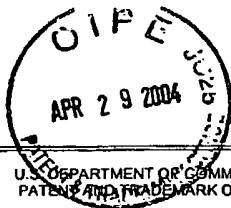


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 248687US0		SERIAL NO. 10/777,179	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Kenji HANABUSA, et al.			
				FILING DATE February 13, 2004		GROUP <del>1614</del> 1654	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	GB 1 485 694	09/14/1977	Great Britain			
	AP	2000-256303	09/19/2000	Japan	Abstract only		X
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<div style="display: flex; align-items: center;"> <div style="font-size: 2em; margin-right: 10px;">↑</div> <div style="font-size: 2em; margin-right: 10px;">↓</div> </div>	AW	D. RANGANATHAN, et al., <u>J. Peptide Res.</u> , vol. 51, pp. 297-302 (1998)					
	AX	S. FRANCESCHI, et al., <u>New J. Chem.</u> , vol. 23, pp. 447-452 (1999)					
	AY	J. MAKAREVIC, et al., <u>Chem. Eur. J.</u> , vol. 7, no. 15, pp. 3328-3341 (2001)					
		M. SUZUKI, et al., <u>Org. Biomol. Chem.</u> , vol. 1, pp. 4124-4131 (2003)					
	AZ	M. SUZUKI, et al., <u>Tetrahedron Letters</u> , vol. 44, pp. 6841-6843 (2003)					<input type="checkbox"/> Additional References sheet(s) attached
Examiner <u>Ph O R</u>							
						Date Considered <u>10/20/04</u>	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 248687US0		SERIAL NO. 10/777,179	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Kenji HANABUSA, et al.			
				FILING DATE February 13, 2004		GROUP 1654	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
ADK ↑	AG	WO 00/53576	09/14/2000	WIPO (with English Abstract)		X	
	AH	2000-344620	12/12/2000	JAPAN (with English Abstract)		X	
	AI	52-66885	06/02/1977	JAPAN (with English Abstract)		X	
	AJ	55-75493	06/06/1980	JAPAN (with English Abstract)		X	
	AK	59-52196	12/18/1984	JAPAN (with English Abstract)		X	
	AL	60-44968	10/07/1985	JAPAN (with English Abstract)		X	
	AM	59-77859	05/04/1984	JAPAN (with English Claim)		X	
	AN	54-33798	10/23/1979	JAPAN (with English Abstract)		X	
	AO	10-273477	10/13/1998	JAPAN (with English Abstract)		X	
	AP	10-237034	09/08/1998	JAPAN (with English Abstract)		X	
	AQ	10-245396	09/14/1998	JAPAN (with English Abstract)		X	
	AR	10-226614	08/25/1998	JAPAN (with English Abstract)		X	
	AS	8-231942	09/10/1996	JAPAN (with English Abstract)		X	
	AT	7-247474	09/26/1995	JAPAN (with English Abstract)		X	
	✓	AU	7-247473	09/26/1995	JAPAN (with English Abstract)		X
ADK	AV	2000-256303	09/19/2000	JAPAN (with English Abstract)		X	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>ML O V</i>					Date Considered <i>10/20/04</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							